

Available software & hardware DAQ systems at LPNHE for Silicon tracker studies



**IXTH SILC MEETING
PARIS, FRANCE**

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Conducted by LPNHE:

- Research baseline: wafer 6"-8", 200 μ m of thickness, pitch of 50 μ m, transparency ~70%, active edge

Edgeless with SOI technology

VTT- Juha Kalliopuska

Manufacturing achievement:

- edgeless & pixels sensors, 6" wafer, 50 μ m pitch

HPK designed by Vienna w/wo surface treatment of silicon wafers(Santander)

- 50 μ m pitch, 320 μ m of thickness
- ~ 20% transmittance
- Alignment System (IFCA) using an infra-red laser in labs & tests beam

3D technology (short strips)

FBK-irst-U. Trento/INFN - Gian Franco Dalla Betta

- 250 μ m thick substrate, full 3D detectors and passing-through columns
- New double-sided process defined, no need for support structure, allow dual read-out

Edgeless planar strips

FBK-irst-U. Trento/INFN - Gian Franco Dalla Betta

- Prototyped sensors 2.5x5cm² (Trento & LPNHE)
- full characterization at Lab followed by beam test & HPK comparison

SiTr130_128 chips

(under developed)



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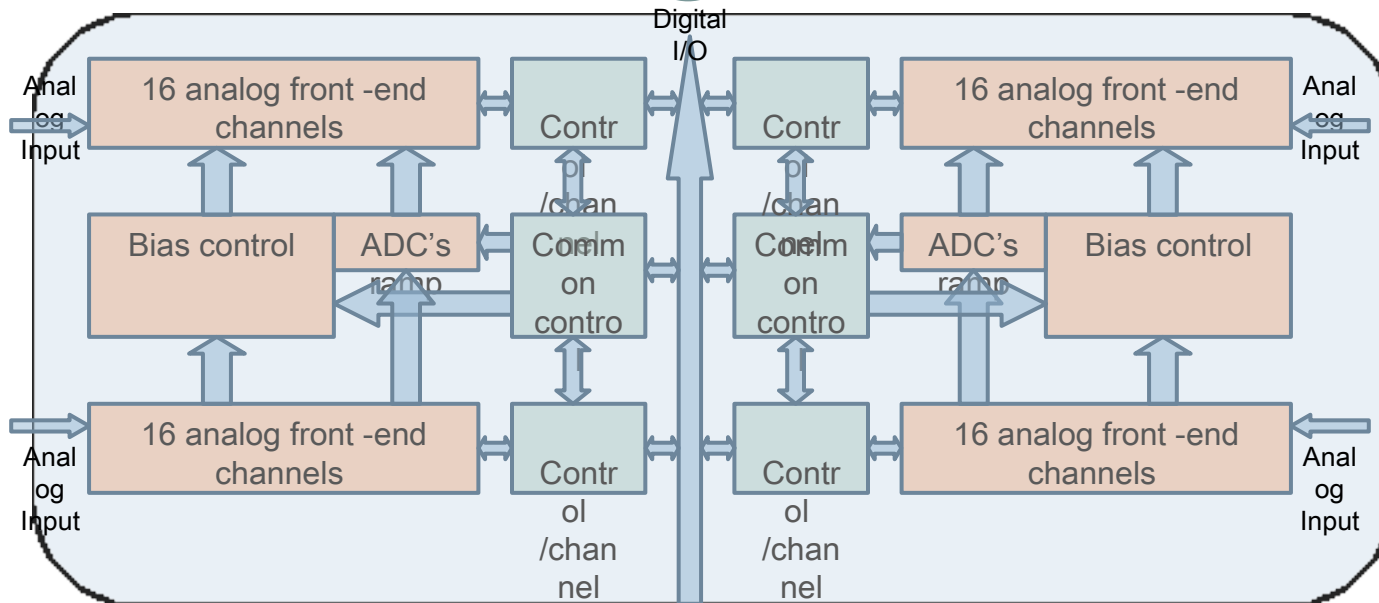
2010 : Conception-achievement and test of the new version of the SiTr130-128 chip → IBM technology, 130nm

- 128 channels + JTAG
- 0.5*1 cm² of silicon, thin down
- Numerical output with pre-amplifier, shaper, reinitialisation, 8x8 analog pipeline for pulse reconstruction, zero suppression, single ramp ADC, integrated numerical control, robustness & flexibility, power cycling, **serialization**
- Goal: **silicon surface optimisation, modular architecture**
- Under Study : direct connection chip/senseur**

SiTr130_128 chips (under developed)



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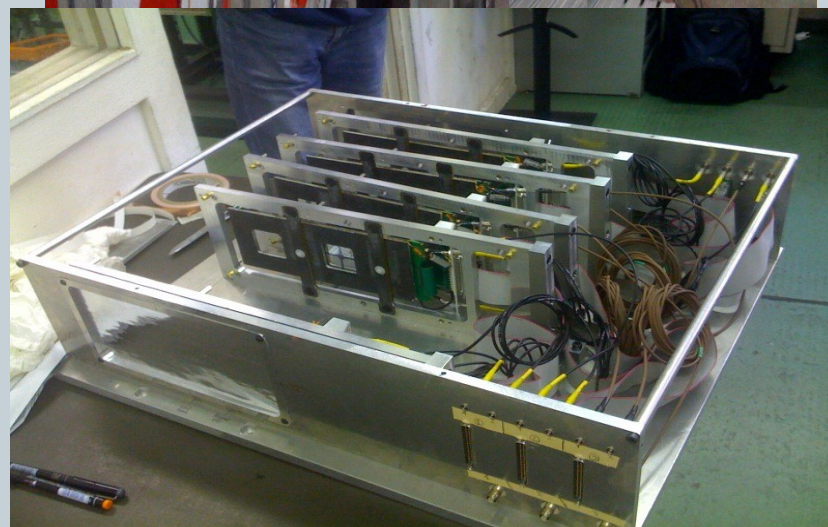
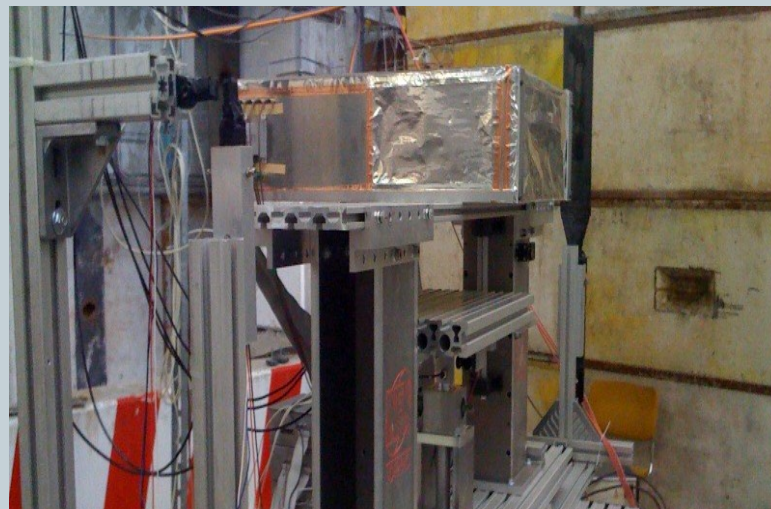


- Zero suppression
- 8x8 analog pipeline for pulse reconstruction
- Single ramp ADC → 10 bits
- Data tagging+timestamping+check >48 bits
- Chips serialization
- i/o @ 48 MHz (final-100MHz)

Comparison with VA1 chip
coupled with 16 bits ADC
used for Si sensor
technology



- Standalone telescope, with five silicon sensors layers: 512 active strips/modules
- Intended to be easily integrated to a test beam
 - High customization
 - All Electronic features In One “AlteraBox”
 - Main functionalities (Peaking Time, Laser Alignment etc...)
 - DAQ – read both FEE systems (new SiTr130-128 chips & VA1)

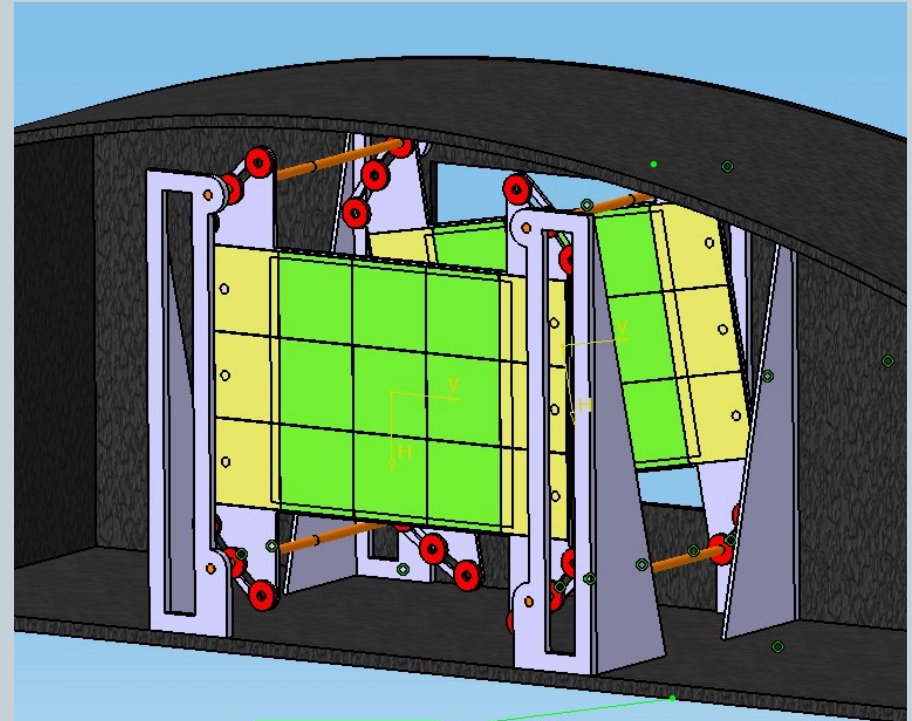




Increase of the number of channel to read:

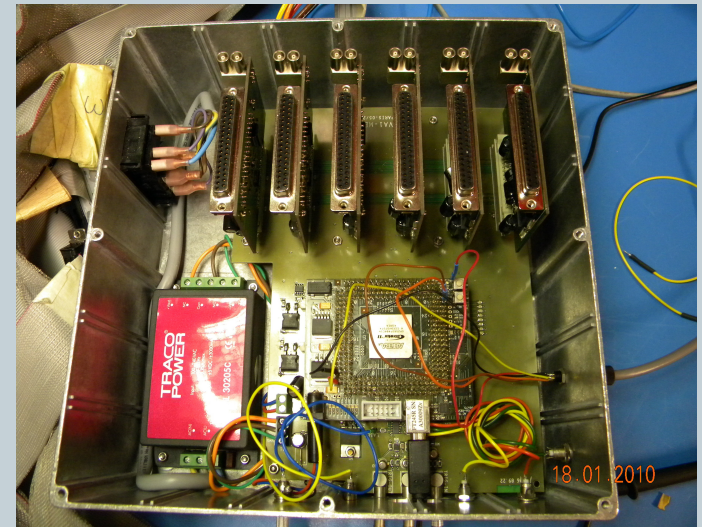
- Nowadays: 2560 channels
- EUDET and transnational tests (mi-2010) => 15000 to 20000 channels
- Update to VA1 to SiTr130-128
- 2011-2012 -> much more !!!

Chip substitution: VA1 → SiTR130-X
(16bits → 64 bits per channel) (see H.PHAM)





- Evolutive DAQ Hardware ToolKit (EUNET deliverable)
 - Adapted to both: VA1 (référence) prototypes SiTr-130 and next, mix mode (VA1+SiTr chips)
 - USB/FPGA interface with microcontroller
 - TTL/NIM for triggering and laser alignment
 - AlteraBox chaining
 - Power supplied embedded
 - **Need to integrate the TLU ?**



Faster serial Interface:

- Ethernet & Light peak (optical link @ 10 Gb) → end of 2010-2011

Development toward the final DAQ design for ILD → link with the mechanical constraint



Acquisition requirement:

- Increasing of the data size management
- Addressing of the data
- On-line control
- High Flexibility

Narval is the main frame (ADA-oriented) <https://forge.in2p3.fr/projects>

→ module programming: ADA/C/C++

→ *Can be easily connected to any global DAQ software → what is needed?*

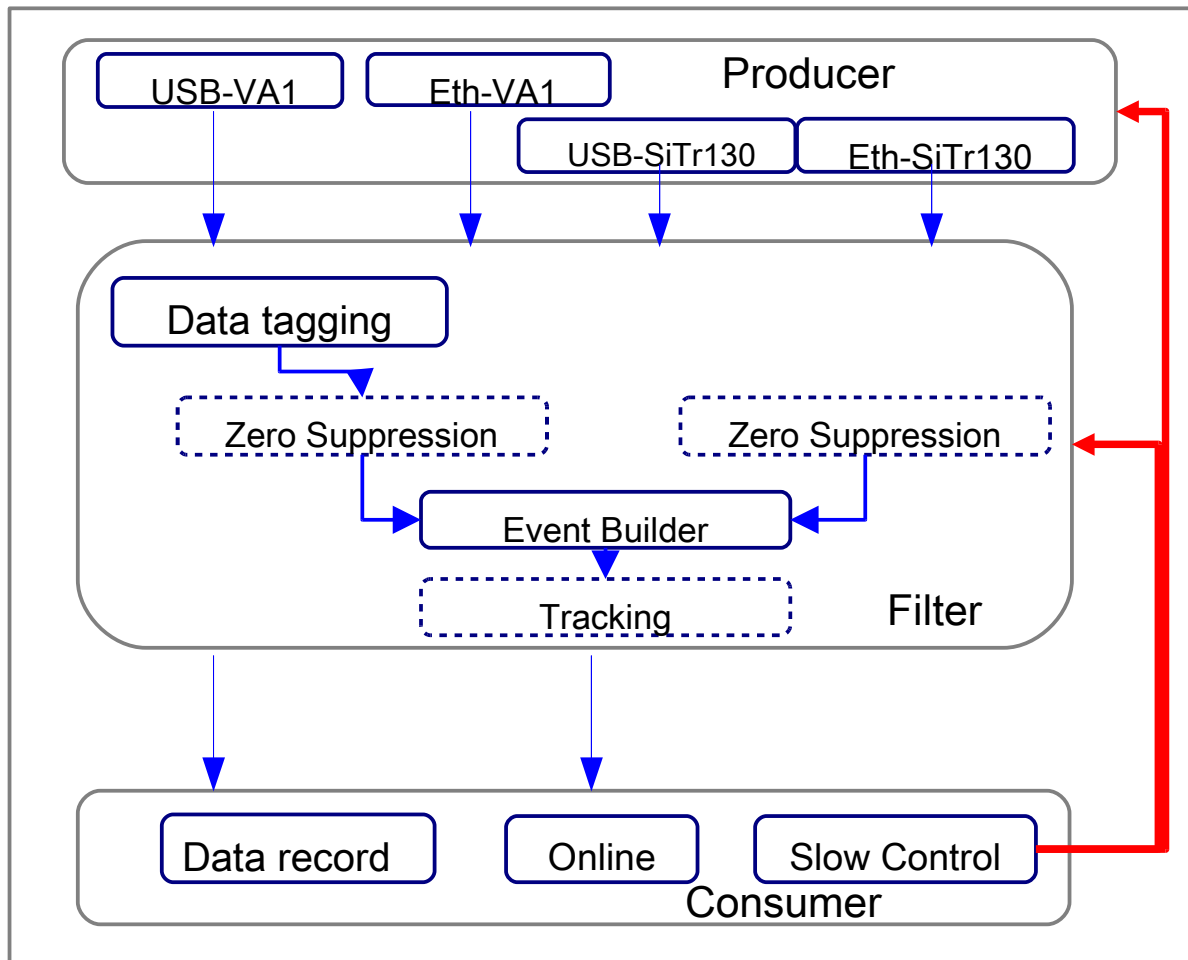
→ *Can easily include another DAQ system*

→ *ENX for the slow Control*

FPGA system is handled by a full VHDL software package



Master: Narval as a linux server

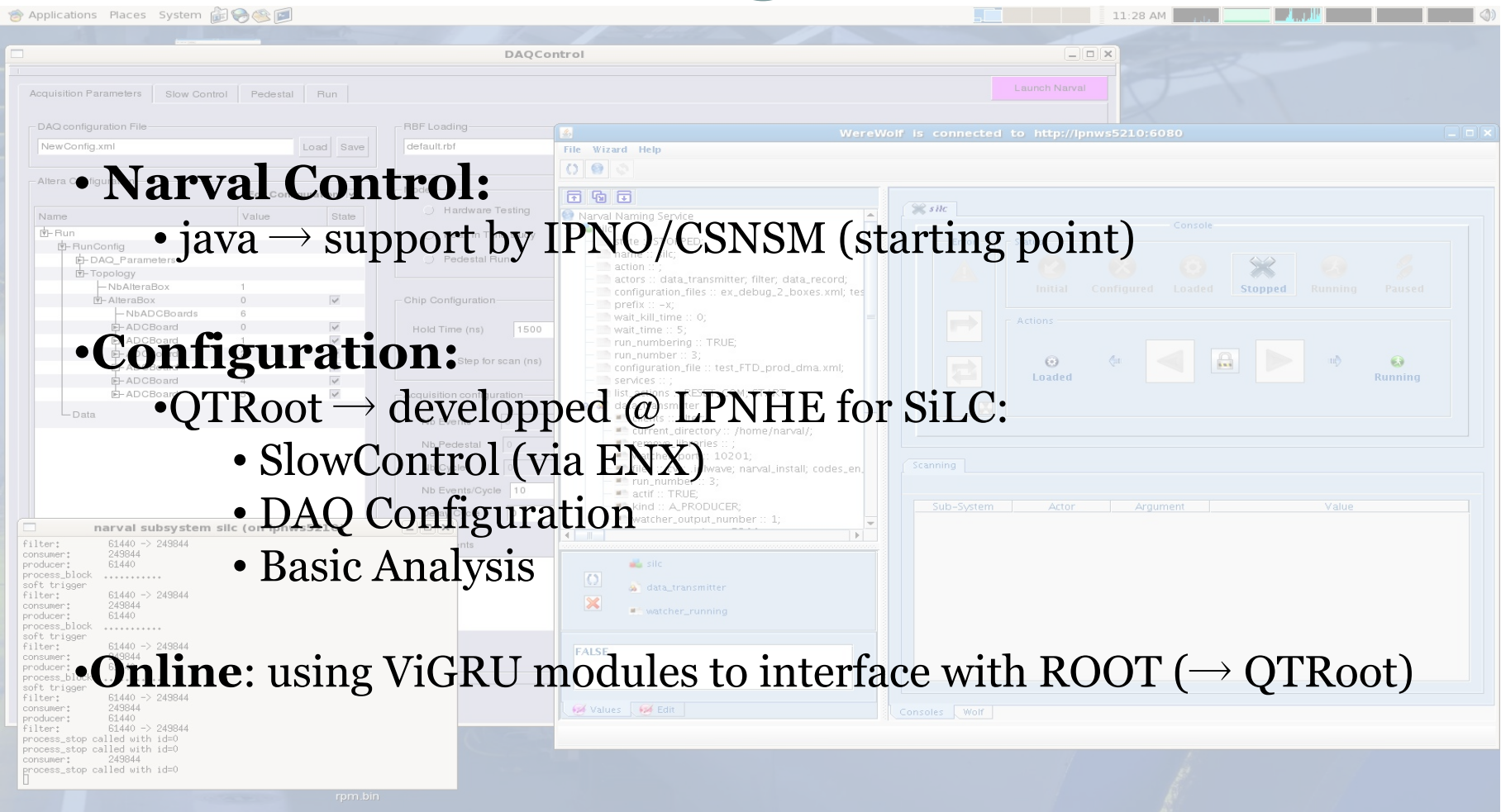


- Three basic actors:
 - Producers
 - Filters
 - Consumers (could be created)

• Dedicated libraries in C/C++/ADA95

• High flexibility with very simple scripts & xml files

Raw Data format for combined test beam ?



• Narval Control:

• java → support by IPNO/CSNSM (starting point)

• Configuration:

• QTRoot → developped @ LPNHE for SiLC:

• SlowControl (via ENX)

• DAQ Configuration

• Basic Analysis

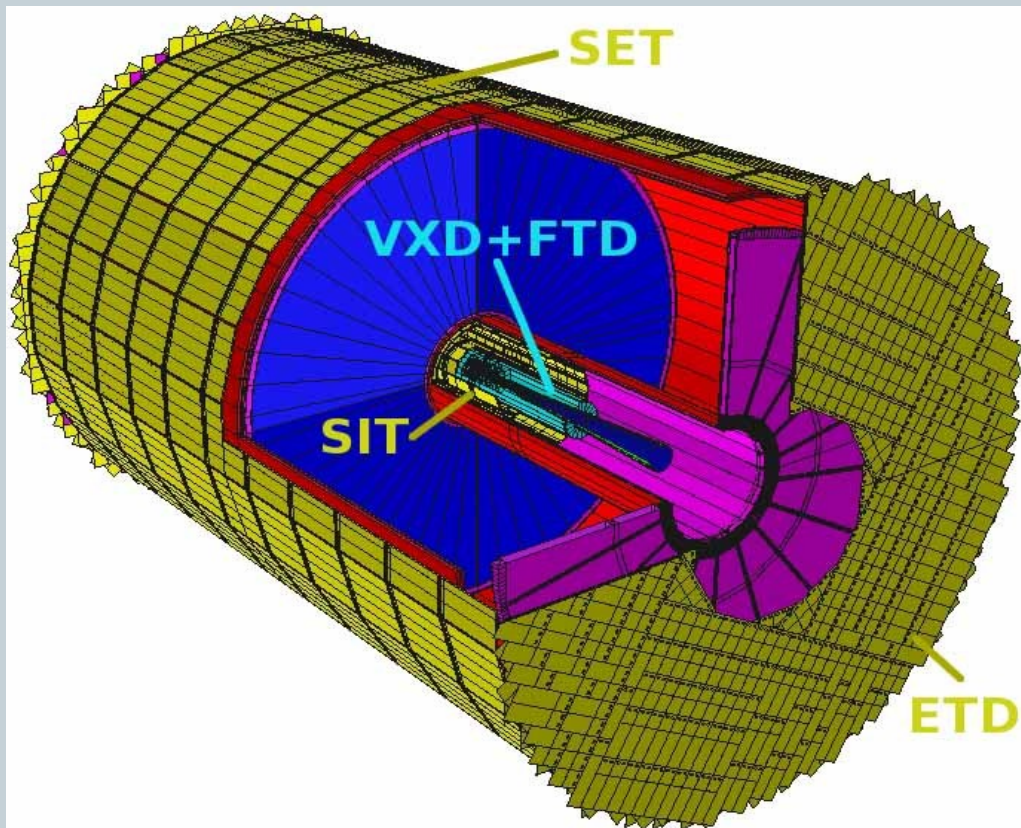
• Online: using ViGRU modules to interface with ROOT (→ QTRoot)

Prospect for 2012

The Silicon Envelope of ILD



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Total number of modules:

500 (SIT) + 2500 (SET) + 2000 (ETDs)

5000 modules of 1792 channels

Total number of channels:

10^6 (SIT) + 5×10^6 (SET) + 4×10^6 (2 ETD)

10×10^6 channels

~5.12 Gbytes

Component	Layer #	# modules	# sensors/ module	# channels	Total surface m2
SIT1	1 st layer	33	3	66.000	0.9
	2 nd layer	99	1	198.000	0.9
SIT2	1 st layer	90	3	180.000	2.7
	2 nd layer	270	1	540.000	2.7
SET	1 st layer	1260	5	2.520.000	55.2
	2 nd layer	1260	5	2.520.000	55.2
ETD_F	X or U or V	82/quad =328/layer =984/ETD	2 or 3 or possibly 4	2.000.000	30
ETD_B	idem	idem	idem	idem	30

Detailed design

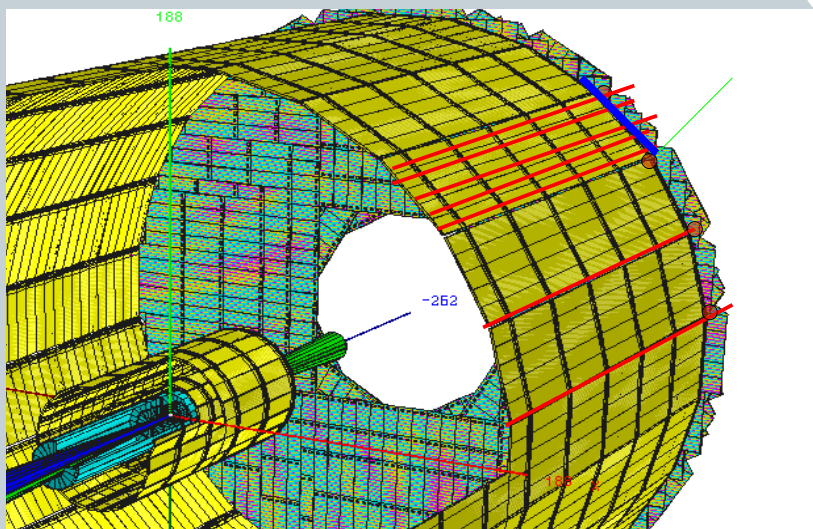
GEANT4 simulation both in MOKKA & ILCROOT
(here) & mechanical design (CATIA) in progress

Prospect for 2012

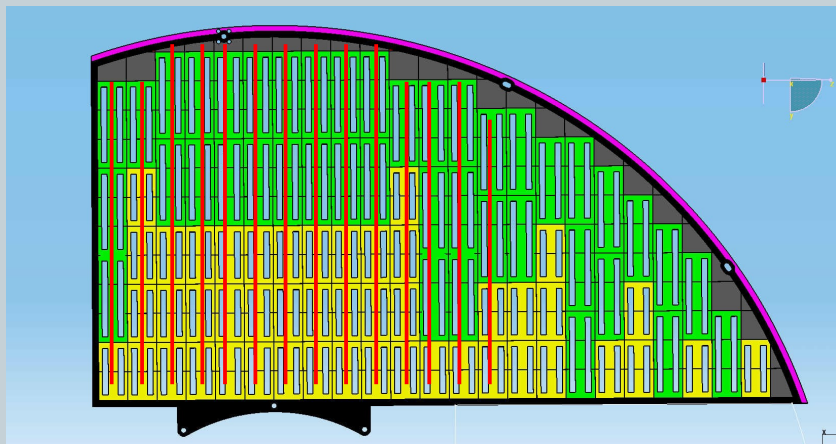
The Silicon Envelope of ILD



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- On the “module”:
Chaining of 14 SiTR130-128
- “Super Module”:
Chaining the adjacent ladders toward a level 1 concentrator
- Half cylinder (“Detector Element”):
Level 1 concentrator (toward level 2 ?)
- Toward the global Silicon DAQ system by Optical fibers
- Send to Global DAQ system



Depending on the final requirements

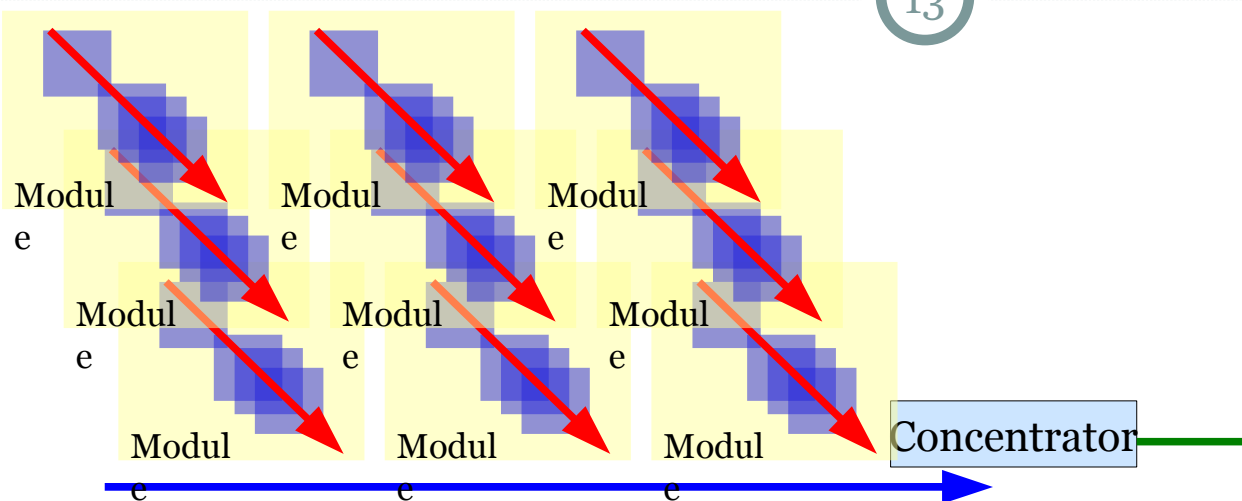
Topology is In progress

DAQ Silicon tracking architecture

A global schematic view of the Silicon DAQ architecture

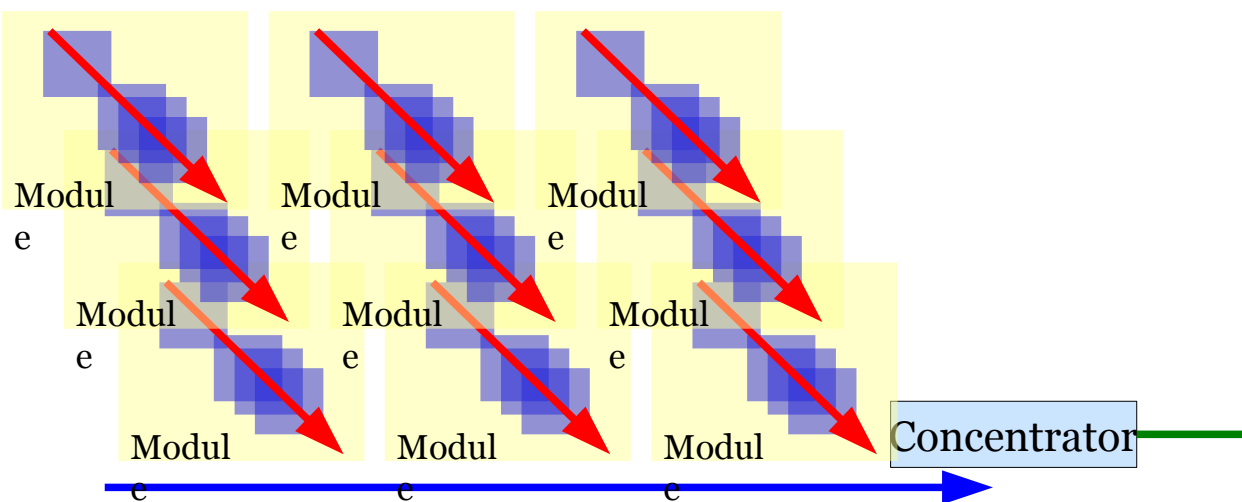


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3 “floors”:

F1: chip on sensor, full readout chain in a single chip (A/D, zero suppression, multiplex ...)



F2: on detector sides, daisy chains chips, data buffering, preprocessing ...

F3: processing, azimuthal sector, track reconstruction

Si Tracking DAQ – ILC workshop, Warsaw



Thanks for your intention